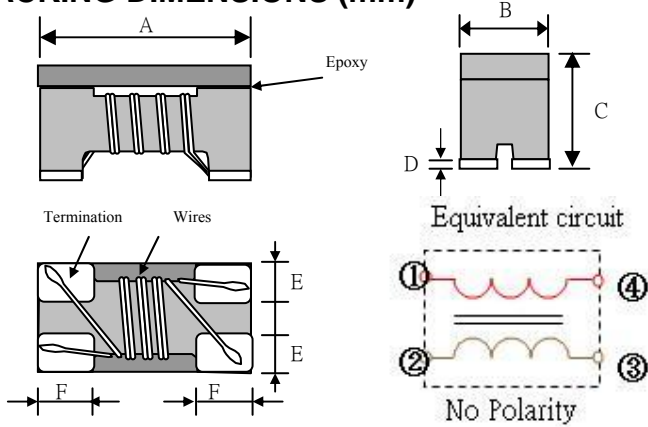


SPECIFICATION

ITEM P/N	BCCUB-T4P-1210HS-SERIES	TEST INSTRUMENT	4287A / 4339B
PRODUCT	COMMON MODE CHOKE	TEST FREQUENCY	100 MHz / 0.5V

PACKING DIMENSIONS (mm)



BCCUB-T4P-1210HS	Dimensions
A	1.2 ± 0.2
B	1.0 ± 0.2
C	0.9 max.
D	0.15 max.
E	0.36Typ.
F	0.33Typ.

Part Numbering

BCCUB	-	T4P	-	1210HS	-	900	-	T
(1)		(2)		(3)		(4)		(5)

- (1) Product name
- (2) Shapes and dimensions
- (3) Shielding Type for USB3.0/7.5G
- (4) Impedance 【 at 100MHz】 900:90Ω
- (5) Tolerance
S = ±25% ; M = ±20%

ELECTRICAL CHARACTERISTICS

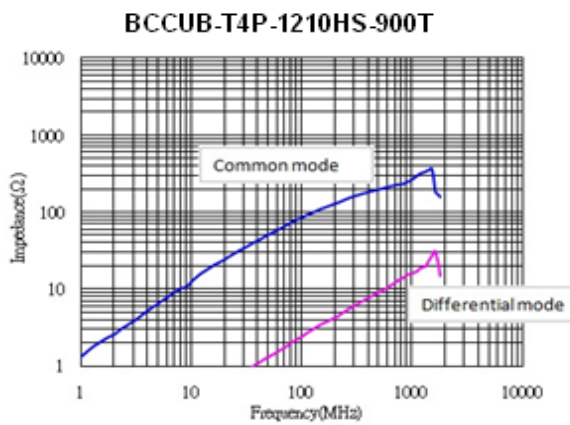
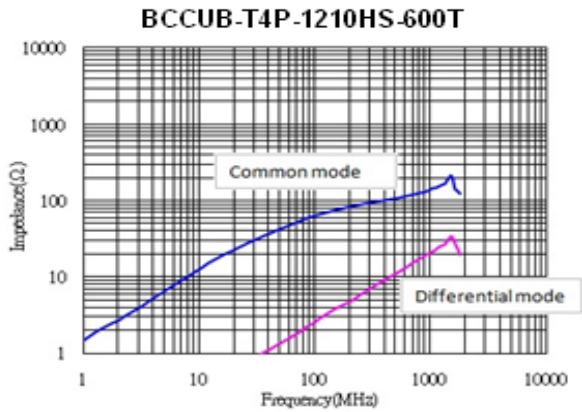
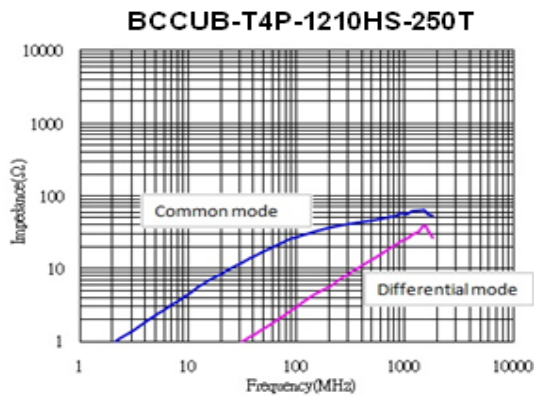
P/N	Z(Ω)	DCR (Ω)	Idc(mA)	Rated Voltage	Insulation Resistance	Cut-off Frequency	Characteristic Resistance
	Common Mode						
	Impedance at 100MHz						
BCCUB-T4P-1210HS-250T	25	0.30	300	20	10	7.5 typ.	90 typ.
BCCUB-T4P-1210HS-600T	60	0.40	300	20	10	7.5 typ.	90 typ.
BCCUB-T4P-1210HS-900T	90	0.50	280	20	10	7.5 typ.	90 typ.

Operating temperature : -25 to +85°C
Storage temp. and humidity : -40 to +85°C ,70%RH max

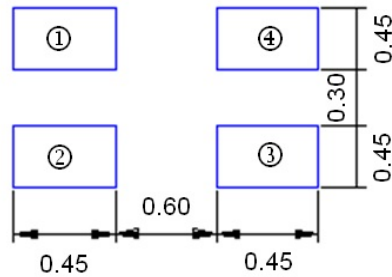
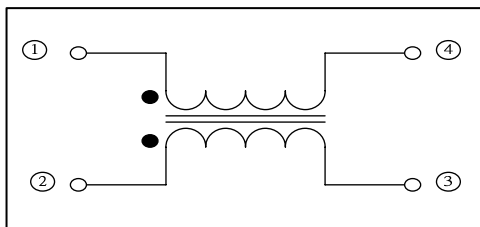
CHARACTERISTICS

ITEM P/N	BCCUB-T4P-1210HS-SERIES	TEST INSTRUMENT	4287A / 4339B
PRODUCT	COMMON MODE CHOKE	TEST FREQUENCY	100 MHz / 0.5V

PERFORMANCE CURVES



Equivalent Circuit & Recommended Footprint



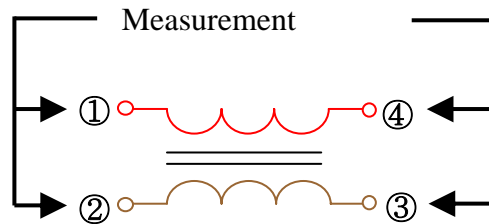
CHARACTERISTICS

ITEM P/N	BCCUB-T4P-1210HS-SERIES	TEST INSTRUMENT	4287A / 4339B
PRODUCT	COMMON MODE CHOKE	TEST FREQUENCY	100 MHz / 0.5V

Test Equipment

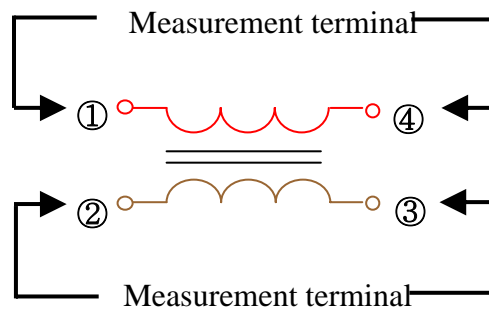
Impedance

Measured by using Agilent 4291A RF Impedance Analyzer.



DC Resistance

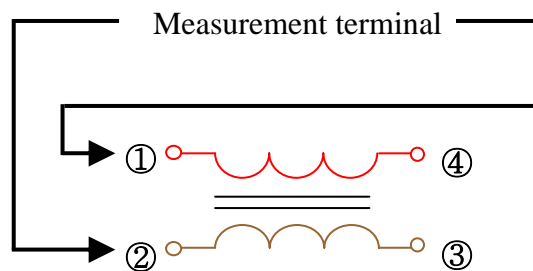
Measured by using Chroma 16502 mill ohm meter.



Insulation Resistance

Measured by using Chroma 19073

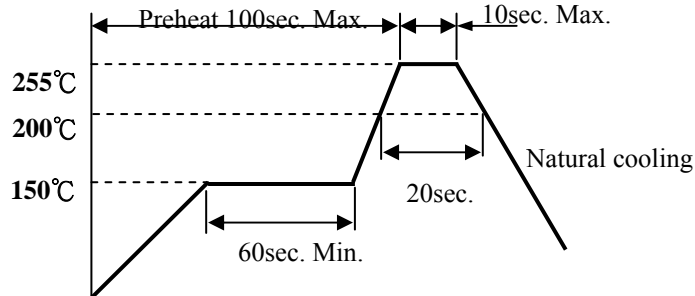
Measurement voltage : 50v ,Measurement time : 60 sec.



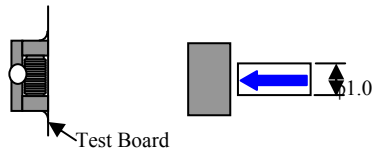
RELIABILITY

ITEM P/N	BCCUB-T4P-1210HS-SERIES	TEST INSTRUMENT	4287A / 4339B
PRODUCT	COMMON MODE CHOKE	TEST FREQUENCY	100 MHz / 0.5V

RECOMMENDED SOLDERING TEMP. GRAPH



MECHANICAL RELIABILITY

TEST	Specification & Requirement	Method Used
Solderability	The surface of terminal/pin tested shall be covered with new solder by 90%	Solder heat proof: Preheating: 150 ±10°C 60 seconds Soldering: 230 ±5°C for 3 ±1 sec
Solder Heat Resistance	Components should have not evidence of electrical and mechanical damage Impedance: within ±15% of initial value	Preheating: 150°C 60secs Solder temperature: 260±5°C Flux: rosin Dip time: 10±0.5 secs
Terminal strength	Series No.	F (Kg)
	BCCUB.-T4P-1210HS	0.2
	BCCUB-T4P-1608HS	0.5
	BCCUB-T4P-2012HS	0.5
	BCCUB-T4P-3216	1.0
		Solder a chip to test substrate and then laterally apply a force in the arrow direction 

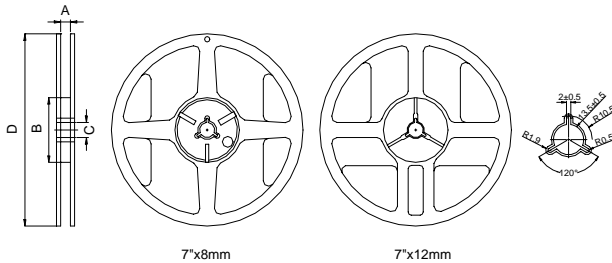
ENDURANCE RELIABILITY

TEST	Specification & Requirement	Method Used
Thermal Shock	Impedance change within ± 15% Without mechanical damage	-65°C, (30 mins) -> room temp. (2 mins) -> 125°C, (30 mins) -> room temp. (2 mins) 50 cycles
Humidity Resistance	Impedance change within ± 15% Without mechanical damage	Apply IDC current @ 60°C ambient Humidity: 90% Duration: 168 hrs
Low Temp. Storing	Impedance change within ± 15% Without mechanical damage	Storing Temp. -40 ±2 °C for total 168 +5/-0 hours
High Temp. Storing	Impedance change within ± 15% Without mechanical damage	Storing Temp. 125 ±2 °C for total 168 +5/-0 hours

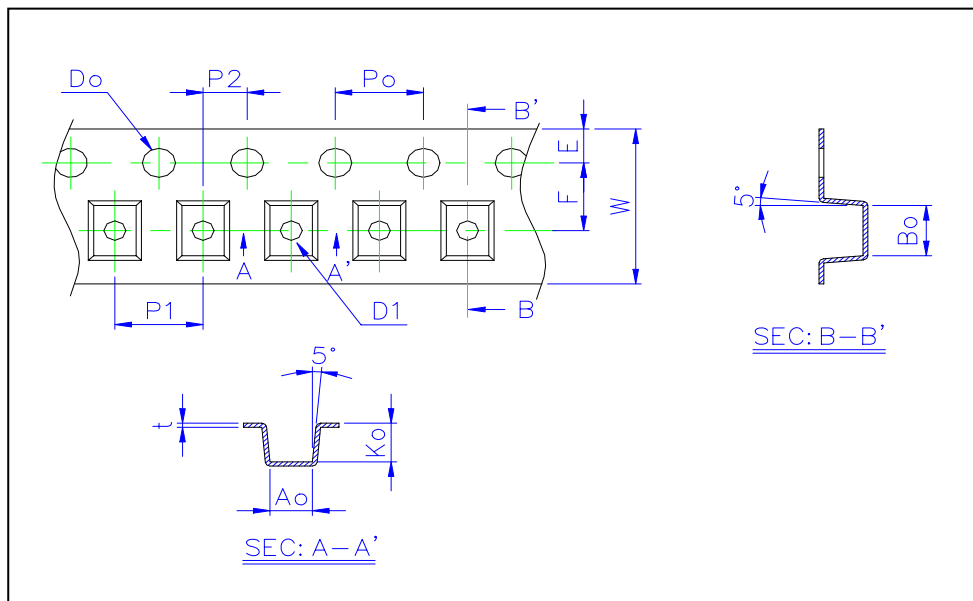
PACKING FOR SMD

ITEM P/N	BCCUB-T4P-1210HS-SERIES	TEST INSTRUMENT	4287A / 4339B
PRODUCT	COMMON MODE CHOKE	TEST FREQUENCY	100 MHz / 0.5V

Reel Dimension & Tape Dimension



Type	A(mm)	B(mm)	C(mm)	D(mm)
7"x8mm	9.0±0.5	60±2	13.5±0.5	178±2
7"x12mm	13.5±0.5	60±2	13.5±0.5	178±2



Size	Ao(mm)	Bo(mm)	Ko(mm)	W(mm)	E(mm)	F(mm)	Po(mm)	P1(mm)	Do(mm)
1210	1.15±0.10	1.40±0.10	0.93±0.10	8.00±0.20	1.75±0.10	3.50±0.05	4.0±0.05	4.0±0.10	1.5+0.1,-0
1608	1.65±0.10	1.00±0.10	1.18±0.10	8.00±0.20	1.75±0.10	3.50±0.05	4.0±0.05	4.0±0.10	1.5+0.1,-0
2012	2.35±0.10	1.50±0.10	1.45±0.10	8.00±0.20	1.75±0.10	3.50±0.05	4.0±0.05	4.0±0.10	1.5+0.1,-0
3216	3.50±0.10	1.88±0.10	2.10±0.10	8.00±0.20	1.75±0.10	3.50±0.05	4.0±0.05	4.0±0.10	1.5+0.1,-0

Packaging Quantity

Chip Size	1210	1608	2012	3216
8mm/ Reel	3000	2000	2000	2000